Special Issue

Artificial Intelligence in Signal, Image and Video Processing

Message from the Guest Editors

Digital image processing has been a topic of active research for many years, and has found application in several fields. In recent years, with the advance of computer technology the use of image processing technology has widely spread in fields, such as information security, biometrics, medicine, image compression, restoration, access control, pattern recognition, image synthesis, and image understanding, among others. We would like to invite the academic and industrial research community to submit original research, as well as review articles to this Special Issue. Topics include:

- Biometric pattern recognition;
- Compressive sensing applications;
- Digital watermarking;
- Image classification;
- Image clustering;
- Image restoration;
- Image authentication;
- Image denoising;
- Image compression;
- Image encryption;
- Face expression recognition;
- Deep learning-based pattern recognition;
- 3D image processing;
- Medical image analysis.

Guest Editors

Prof. Dr. Héctor Manuel Pérez-Meana
Instituto Politécnico Nacional, ESIME Culhuacan, Av. Santa Ana No. 1000, Ciudad de México 04440, Mexico

Prof. Dr. Mariko Nakano-Miyatake
Instituto Politécnico Nacional, Av. Santa Ana 1000, Coyoacan, Mexico City CP4040, Mexico

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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